



#### 3.3V Very Low Power 2-Output PCIe Clock Generator With On-chip Termination

#### **Features**

- → 3.3V Supply Voltage
- → Crystal/CMOS input: 25 MHz
- → 2 Differential low power HCSL outputs with on-chip termination
- → Default  $Z_{OUT} = 85\Omega$
- → Individual output enable
- → Reference CMOS output
- → Programmable slew rate and output amplitude for each output
- → Differential outputs blocked until PLL is locked
- → Selectable 0%, -0.25% or -0.5% spread on differential outputs
- → Strapping pins or SMBus for configuration
- → Differential Output-To-Output Skew <50ps
- → Very-Low Jitter Outputs
  - Differential Cycle-To-Cycle Jitter <50ps</li>
  - PCIe Gen1/Gen2/Gen3/Gen4/Gen5 Compliant
  - CMOS REFOUT Phase Jitter
    - < 0.3ps RMS, SSC off
    - <1.5ps RMS, SSC on
- → Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- → Halogen and Antimony Free. "Green" Device (Note 3)
- → For automotive applications requiring specific change control (i.e. parts qualified to AEC-Q100/101/200, PPAP capable, and manufactured in IATF 16949 certified facilities), please contact us or your local Diodes representative.

https://www.diodes.com/quality/product-definitions/

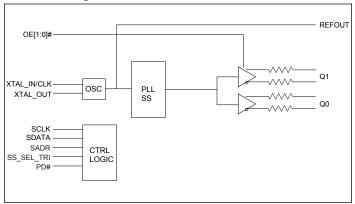
→ Packaging (Pb-free & Green): 24-lead 4×4mm TQFN

#### Description

The PI6CG33202C is a 2-output very low power PCIe Gen1/Gen2/ Gen3/Gen4/Gen5 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low power differential HCSL outputs with on-chip terminations. The on-chip termination can save 8 external resistors and make layout easier. An additional buffered reference output is provided to serve as a low noise reference for other circuitry.

It uses Diodes' proprietary PLL design to achieve very low jitter that meets PCIe Gen1/Gen2/Gen3/Gen4/Gen5 requirements. It also provides various options such as different slew rate and amplitude through SMBUS so that users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spread-spectrum options to reduce EMI for various applications.

#### **Block Diagram**



#### Notes:

antimony compounds.

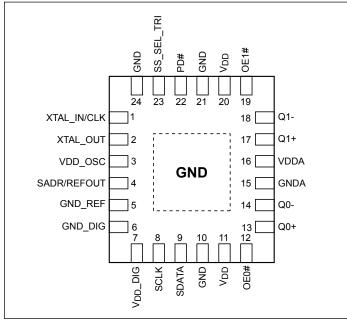
<sup>1.</sup> No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

<sup>2.</sup> See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free. 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm





# **Pin Configuration**



#### **Pin Description**

Pin #	Pin Name	Ту	pe	Description
1	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
2	XTAL_OUT	Output		Crystal output
3	V <sub>DD_OSC</sub>	Power		Power supply for oscillation circuit, nominal 3.3V
4	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or LVCMOS REFOUT. This pin has an internal pull-down
5	GND_REF	Power		Ground for REFOUT
6	GND_DIG	Power		Ground for digital circuitry
7	V <sub>DD</sub> _DIG	Power		Power supply for digital circuitry, nominal 3.3V
8	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
9	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
10, 21, 24	GND	Power		Ground pin
11, 20	V <sub>DD</sub>	Power		Power supply, nominal 3.3V
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
15	GNDA	Power		Ground for analog circuitry
16	V <sub>DDA</sub>	Power		Power supply for analog circuitry





In Description Cont.							
Pin #	Pin Name	Ту	pe	Description			
17	Q1+	Output	HCSL	Differential true clock output			
18	Q1-	Output	HCSL	Differential complementary clock output			
19	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pull- down.			
				1 =disable outputs, 0 = enable outputs			
22	PD#	Input	CMOS	Input notifies device to sample latched inputs and start up on first high assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor.			
23	SS_SEL_TRI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up. 1 = $0.5\%$ spread, M = Spread off, 0 = Spread off. The pin has both internal pull-up and pull-down. Refer to SMBUS byte_1 bit 4, 3 = '01' to get - $0.25\%$ spread.			
Epad	GND	Power		Connect to Ground			

#### **Pin Description Cont**





#### **SMBus Address Selection Table**

	SADR	Address	+Read/Write Bit
	0	1101000	Х
State of SADR on first application of PD#	1	1101010	Х

#### Power Management Table<sup>(3)</sup>

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	Х	Х	Low <sup>(1)</sup>	Low <sup>(1)</sup>	HiZ <sup>(2)</sup>
1	1	0	Running	Running	Running
1	1	1	Disabled <sup>(1)</sup>	Disabled <sup>(1)</sup>	Running
1	0	Х	Disabled <sup>(1)</sup>	Disabled <sup>(1)</sup>	Disabled <sup>(4)</sup>

1. The output state is set by B11[1:0] (Low/Low default)

2. REF is Hi-Z until the 1st assertion of PD# high. After this, when PD# is low, REF is disabled. If Byte3, bit 5 = 1, then REF is running

3. Input High/ Low defined at default values for device

4. See SMBUs Byte 3, bit 4





#### **Maximum Ratings**

(Above which useful life may be impaired. For user guidelines, not tested.)

Storage Temperature	65°C to +150°C
117 0	$V_{DDxx} = 0.5 V \text{ to } +4.6 V$
Input Voltage	-0.5V to VDD+0.5V, not exceed 4.6V
SMBus, Input High Voltage	
ESD Protection (HBM)	
Max Junction Temperature	+125°C

Note: Stresses greater than those listed under MAXI-MUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

### **Operating Conditions**

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DD</sub> , V <sub>DDA</sub> , V <sub>DD</sub> _OSC, V <sub>DD</sub> _DIG,	Power Supply Voltage		3.135	3.3	3.465	v
I <sub>DDA</sub>	Analog Power Supply Current	All outputs active @100MHz		22	25	mA
I <sub>DD</sub>	Power Supply Current <sup>(3)</sup>	All $V_{DD}$ , except $V_{DDA}$ , All outputs active @100MHz		24	30	mA
I <sub>DDA_WL</sub>	Analog Power Supply Wake-on- LAN <sup>(1)</sup> Current	Q outputs off, REF output running		0.5	1.0	mA
I <sub>DD_WL</sub>	Power Supply Wake-on-LAN <sup>(1)</sup> Current	All $V_{DD}$ , except $V_{DDA}$ , Q outputs off, REF output running		3.0	6.0	mA
I <sub>DDA_PD</sub>	Analog Power Supply Power Down <sup>(2)</sup> Current	All outputs off		0.5	1.0	mA
I <sub>DD_PD</sub>	Power Supply Power Down <sup>(2)</sup> Current	All outputs off		1.0	2.0	mA
T <sub>A</sub>	Ambient Temperature	Industrial grade	-40		85	°C

Note:

1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'

2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'

3. Output drive 5 inch trace.





#### **Input Electrical Characteristics**

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R <sub>pu</sub>	Internal pull up resistance			120		KΩ
R <sub>dn</sub>	Internal pull down resistance			120		KΩ
C <sub>XTAL</sub>	Internal capacitance on X_IN and X_OUT pins			8		pF
L <sub>PIN</sub>	Pin inductance				7	nH

### **Crystal Characteristic**

Parameters	Description	Min.	Тур	Max.	Units
OSCmode	Mode of Oscillation	F	Fundamental		
FREQ	Frequency		25		MHz
ESR <sup>(1)</sup>	Equivalent Series Resistance			50	Ω
Cload	Load Capacitance		8		pF
Cshunt	Shunt Capacitance			7	pF
	Drive Level			200	uW

Note:

1. ESR value is dependent upon frequency of oscillation

# **SMBus Electrical Characteristics**

Temperature =  $T_A$ ; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DDSMB</sub>	Nominal bus voltage		2.7		3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1		3.6	
V <sub>IHSMB</sub>	SMBNominal bus voltage2.7SMBNominal bus voltage $2.7$ SMBSMBus Input High VoltageSMBus, $V_{DDSMB} = 3.3V$ $2.1$ SMBSMBus Input High Voltage $SMBus, V_{DDSMB} < 3.3V$ $0.65$ $V_{DDSMB}$ MBSMBus Input Low VoltageSMBus, $V_{DDSMB} = 3.3V$ $0.65$ $V_{DDSMB}$ SINKSMBus sink currentSMBus, $V_{DDSMB} < 3.3V$ $0.65$ $V_{DDSMB}$ SINKSMBus sink currentSMBus, $V_{DDSMB} < 3.3V$ $0.65$ $V_{DDSMB}$ SMBSMBus output Low VoltageSMBus, at $V_{OLSMB}$ $4$ SMBSMBus Output Low VoltageSMBus, at $I_{SMBSINK}$ $4$ SMBSMBus operating frequencyMaximum frequency $0.65$ $V_{DDSMB}$ BSMBus rise time $(Max V_{IL} - 0.15)$ to $(Min V_{IH} + 0.15)$ $0.65$ $V_{DDSMB}$			V		
N		SMBus, $V_{DDSMB} = 3.3V$			0.8	V
V <sub>ILSMB</sub> I <sub>SMBSINK</sub>	SMBus Input Low Voltage	SMBus, V <sub>DDSMB</sub> < 3.3V			0.8	
I <sub>SMBSINK</sub>	SMBus sink current	SMBus, at V <sub>OLSMB</sub>	4			mA
VOLSMB	SMBus Output Low Voltage	SMBus, at I <sub>SMBSINK</sub>			0.4	V
f <sub>MAXSMB</sub>	SMBus operating frequency	Maximum frequency			500	kHz
t <sub>RMSB</sub>	SMBus rise time	(Max $V_{IL}$ - 0.15) to (Min $V_{IH}$ + 0.15)			1000	ns
t <sub>FMSB</sub>	SMBus fall time	(Min V <sub>IH</sub> + 0.15) to (Max V <sub>IL</sub> - 0.15)			300	ns

# **Spread Spectrum Characteristic**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f <sub>MOD</sub>	SS Modulation Frequency	Triangular modulation	30	31.8	33	kHz





# **LVCMOS DC Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>IH</sub>	Input High Voltage	Single-ended inputs, except SMBus	0.75 V <sub>DD</sub>		V <sub>DD</sub> +0.3	V
V <sub>IM</sub>	Input Mid Voltage	SS_SEL_TRI	$0.4 V_{DD}$	$0.5 V_{\rm DD}$	$0.6V_{\rm DD}$	V
V <sub>IL</sub>	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 V <sub>DD</sub>	V
I <sub>IH</sub>	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			5	μA
I <sub>IL</sub>	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-5			μA
I <sub>IH</sub>	Input High Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = V_{DD}$			50	μΑ
I <sub>IL</sub>	Input Low Current	Single-ended inputs with pull up / pull down resistor, $V_{IN} = 0V$	-50			μA
V <sub>OH</sub>	Output High Voltage	REFOUT, except SMBus; I <sub>OH</sub> = -2mA	0.8 x V <sub>DD</sub> Refout			V
V <sub>OL</sub>	Output Low Voltage	REFOUT, except SMBus; I <sub>OL</sub> = 2mA			0.2 x V <sub>DD</sub> _ refout	V
R <sub>OUT</sub>	CMOS Output impedance			20		Ω
C <sub>IN</sub>	Input Capacitance		1.5		5	pF





## **LVCMOS AC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f <sub>INPUT</sub>	Input Frequency	XTAL_IN/CLK		25		MHz
t <sub>RIN</sub>	Input rise time	Single-ended inputs			5	ns
t <sub>FIN</sub>	Input fall time	Single-ended inputs			5	ns
t <sub>STAB</sub>	Clock stabilization	From Power-Up and after input clock stabi- lization or de-assertion of PD# to 1st clock		0.75	1	ms
t <sub>OELAT</sub>	Output enable latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
t <sub>PDLAT</sub>	PD# de-assertion	Differential outputs enable after PD# de- assertion		20	300	us
t <sub>PERIOD</sub>	REFOUT clock period	REFOUT, assume input is at 25MHz		40		ns
f <sub>ACC</sub>	REFOUT frequency accuracy <sup>(1)</sup>	REFOUT, long term accuracy to input		0		ppm
		Byte 3 = 1F, 20% to 80% of $V_{DDREF}$	0.9	1.4	2	V/ns
tRINItFINItFINItSTABItOELATItPDLATItPERIODIfACCItSLEWItDCItDCDISItJITCCItJITPHI	REFOUT slew rate <sup>(1)</sup>	Byte 3 = 5F, 20% to 80% of $V_{DDREF}$	1.5	2.4	3.2	V/ns
	REFOUT siew rate <sup>(*)</sup>	Byte 3 = 9F, 20% to 80% of $V_{DDREF}$	2	3	3.8	V/ns
		Byte 3 = DF, 20% to 80% of $V_{DDREF}$	2.3	3.2	4	V/ns
t <sub>DC</sub>	REFOUT Duty Cycle <sup>(1)</sup>	$V_{\rm T} = V_{\rm DD}$ /2 V, driven by a Xtal	45	50	55	%
t <sub>DCDIS</sub>	REFOUT Duty Cycle Distor- tion	$V_{\rm T} = V_{\rm DD}$ /2 V, driven by an external source	-2	0	+2	%
t <sub>JITCC</sub>	REFOUT cycle-cycle jitter	$V_{\rm T} = V_{\rm DD}$ /2 V, driven by a Xtal		70	150	ps
t	REFOUT Phase Jitter, RMS	12kHz to 5MHz, SSC off, driven by a Xtal		0.16	0.3	ps
ЧТРН	KEFOUI Pliase Jiller, KMS	12kHz to 5MHz, SSC on, driven by a Xtal		0.9	1.5	ps
t	Noise floor	1kHz offset, driven by a Xtal		-149	-135	dBc/Hz
YITN	INOISE HOOF	10kHz offset to Nyquist, driven by a Xtal		-158	-140	dBc/Hz

Note:

1. Guaranteed by design and characterization, not 100% tested in production





# **HCSL Output Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V <sub>OH</sub>	Output Voltage High <sup>(1)</sup>	Statistical measurement on single-ended	660	784	850	mV
VOL	Output Voltage Low <sup>(1)</sup>	signal using oscilloscope math function	-150		150	mV
VOMAX	Output Voltage Maximum <sup>(1)</sup>	Measurement on single ended signal using		816	1150	mV
V <sub>OMIN</sub>	Output Voltage Minimum <sup>(1)</sup>	absolute value	-300	-42		mV
V <sub>OC</sub>	Output Cross Voltage <sup>(1,2,4)</sup>		250	430	550	mV
DV <sub>OC</sub>	V <sub>OC</sub> Magnitude Change <sup>(1,2,5)</sup>			12	140	mV

Note:

1. At default SMBUS amplitude settings

2. Guaranteed by design and characterization, not 100% tested in production

3. Measured from differential waveform

4. This one is defined as voltage where Q+ = Q- measured on a component test board and only applied to the differential rising edge

5. The total variation of all Vcross measurements in any particular system. This is a subset of Vcross\_min/max allowed.

# **HCSL Output AC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
f <sub>OUT</sub>	Output Frequency			100		MHz
1	Slew rate <sup>(1,2,3)</sup>	Scope averaging on fast setting	2.5	3.2	4	V/ns
t <sub>RF</sub>	Slew rate (1,2,5)	Scope averaging on slow setting	2.2	3	3.7	V/ns
Dt <sub>RF</sub>	Slew rate matching <sup>(1,2,4)</sup>	Scope averaging on		7	15	%
t <sub>DC</sub>	Duty Cycle <sup>(1,2)</sup>	Measured differentially, PLL Mode	45	50	55	%
t <sub>SKEW</sub>	Output Skew <sup>(1,2)</sup>	Averaging on, $V_T = 50\%$		20	50	ps
tj <sub>c-c</sub>	Cycle to cycle jitter <sup>(1,2)</sup>			20	50	ps





#### **HCSL Output AC Characteristics Cont.**

Symbol	Parameters	Condition	Min.	Тур.	Max	Spec Limit	Units
		PCIe Gen 1 <sup>(6)</sup>		20	30	86	ps(p-p)
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz		0.08	0.1	3.0	ps
		PCIe Gen 2 High Band, 1.5MHz < f < Nyquist (50MHz)		0.99	1.3	3.1	ps
tj <sub>PHASE</sub>	Integrated Phase Jitter (RMS) <sup>(1,5)</sup>	PCIe Gen3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)		0.32	0.42	1.0	ps
		PCIe Gen3 Separate Reference No Spread (PLL BW of 2-4 or 2-5MHz, CDR =10 MHz)		0.16	0.21	0.7	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)		0.32	0.4	0.5	ps
		PCIe Gen 5 <sup>(7)</sup> (PLL BW of 500k to 1.8MHz. CDR = 20MHz)		0.02	0.05	0.15	ps
tj <sub>PH-</sub> srisg2	Integrated Phase Jitter (RMS), -0.25% Spread	PCIe Gen 2, Separate Reference Inde- pendent Spread (PLL BW of 16MHz, CDR=5MHz)		0.6	0.92	2	ps
tj <sub>PH-</sub> SRISG3	Integrated Phase Jitter (RMS), -0.25% Spread	PCIe Gen 3, Separate Reference Inde- pendent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)		0.32	0.4	0.7	ps
tj <sub>PH-</sub> SRISG2	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 2, Separate Reference Inde- pendent Spread (PLL BW of 16MHz, CDR=5MHz)		0.8	1.1	2	ps
tj <sub>PH-</sub> SRISG3	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 3, Separate Reference Inde- pendent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)		0.35	0.6	0.7	ps

#### Note:

1. Guaranteed by design and characterization—not 100% tested in production.

2. Measured from differential waveform.

3. Slew rate is measured through the Vswing voltage range centered around differential 0V, within ±150mV window.

4. It is measured using a ±75mV window centered on the average cross point.

5. See http://www.pcisig.com for complete specs.

6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of  $10^{-12}$ .

7. PCIe Gen 5 v0.9 specification.





#### **Differential Output Clock Periods - Spread Spectrum Disabled**

			Mea	surement Wir	ndow			
Center	1 clock	1 µs	0.1 s	0.1 s	0.1 s	1 µs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

# **Differential Output Clock Periods - Spread Spectrum Enabled**

			Mea	surement Wir	ndow			
Center	1 clock	1 µs	0.1 s	0.1 s	0.1 s	1 µs	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

#### Note:

1. Guaranteed by design and characterization-not 100% tested in production.

2. All long term accuracy and clock period specifications are guaranteed assuming REF is trimmed to 25MHz.





# **SMBus Serial Data Interface**

PI6CG33202C is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

#### **Address Assignment**

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

#### How to Write

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

#### How to Read

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bi	ts	1 bit	<b>8 b</b> i	its	1 bit	
Start bit	Address	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Repeat Start bit	Address	R(1)	Ack		Byte t = X	Ack	-	inning a Byte	Ack	
											8 bit	6		1 bit	1 bit	
											Data l	Byte		NAck	Stop bit	
											(N+X-	-1)		NACK	Stop bit	

#### Byte 0: Output Enable Register<sup>(1)</sup>

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	Reserved			0		
3	Reserved			0		
2	Q1_OE	Q1 output enable	RW	1	See B11[1:0]	Pin Control
1	Q0_OE	Q0 output enable	RW	1	See B11[1:0]	Pin Control
0	Reserved			0		

#### Note:

1. A low on these bits will override the OE# pins and force the differential outputs to the state indicated by B11[1:0] (Low/ Low default)





#### **Byte 1: SS Spread Spectrum and Control Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1	
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL	_TRI = '0',	
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'10' for SS_SEL_ '11' for SS_SEL_	-	
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount	
4	SSENSW1	SS enable SW control Bit1	RW <sup>(1)</sup>	0	'00' = SS off, '01	' = -0.25% SS,	
3	SSENSW0	SS enable SW control Bit0	RW <sup>(1)</sup>	0	'10' = SS off, '11'	= -0.5% SS	
2	Reserved			1			
1	Amplitude1	Control output organitudo	RW	1	'00' = 0.6V, '01' =	= 0.68V, '10' =	
0	Amplitude0	Control output amplitude	RW	0	0.75V, '11' = 0.85V		

#### Note:

1. Spread must be selected OFF or ON with the hardware latch pin. These bits should not be used to turn spread ON or OFF after power up. These bits can be used to change the spread amount, and B1[5] must be set to a 1 for these bits to have any effect on the part. If These bits are used to turn spread OFF or ON, the system will need to be reset.

# **Byte 2: Differential Output Slew Rate Control Register**

Bit	<b>Control Function</b>	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Reserved			1		
2	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting
1	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting
0	Reserved			1		





## **Byte 3: REF Control Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7			RW	0	'00' = 1.4V/ns '0	01' = 2.4V/ns,
6	REFSLEWRATE	Slew rate control for REF	RW	1	'10' = 3V/ns, '11	' = 3.2V/ns
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = Dis- abled in PD state <sup>(1)</sup>	REF = run- ning in PD state
4	REF_OE	Output enable for REF	RW	1	REF = Dis- abled <sup>(1)</sup>	REF = run- ning
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

Note:

1. The disabled state depends on Byte11[1:0]. '00' = Low, '01'=HiZ, '10'=Low, '11'=High

#### **Byte 4: Reserved**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved			0x40		

#### **Byte 5: Revision and Vendor ID Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1	
7	RID3		R	0			
6	RID2		R	0	rev = 0000		
5	RID1	Revision ID	R	0			
4	RID0		R	0			
3	PVID3		R	0			
2	PVID2		R	0	D: 1 0011		
1	PVID1	Vendor ID	R	1	Diodes = 0011		
0	PVID0		R	1			





## Byte 6: Device Type/Device ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1	
7	DTYPE1		R	0	'00' = CG, '01' =	ZDB,	
6	DTYPE0	Device type	R	0	'10' = Reserve, '11' = NZDB		
5	DID5		R	0	- - 000010 binary, 02Hex		
4	DID4		R	0			
3	DID3		R	0			
2	DID2	Device ID	R	0			
1	DID1		R	1			
0	DID0		R	0	1		

#### **Byte 7: Byte Count Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	BC4		RW	0		
3	BC3		RW	1	Writing to this	register will
2	BC2	Byte count programming	RW	0	configure how many bytes w be read back, default is 8 byt	
1	BC1		RW	0		
0	BC0		RW	0		

#### Byte 8 and 9: Reserved

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved			B8: 0x36 B9:0x00		

#### **Byte 10: PD Restore**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	PD Restore	PD Restore to default configuration	RW	1	Clear PD Config	Keep PD Config
5:0	Reserved			0		





### Byte 11: Stop Control

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:2	Reserved			0		
1	STP1	rue/ Compliment DIF Output Disable Sate	RW	0	00= Low/Low	10= High/ Low
0	STP0		RW	0	01= HiZ/HiZ	11= Low/High

#### **Byte 12: Impedance Control**

Bit	<b>Control Function</b>	Description	Туре	Power Up Condition	0	1
7	Q0_Zout1	Q0 Zout	RW			
6	Q0_Zout0	Q0 Zout	RW			
5	Reserved			00 = Reserved		
4	Reserved				$01 = 85\Omega$	
3	Reserved			- 01	$10 = 100\Omega$	
2	Reserved			11 = Reserved		
1	Reserved					
0	Reserved					

#### **Byte 13: Impedance Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved					
6	Reserved					
5	Reserved	Reserved			00 = Reserved	
4	Reserved			01	$01 = 85\Omega$ $10 = 100\Omega$	
3	Q1_Zout1	Q1 Zout	RW	01		
2	Q1_Zout0	Q1 Zout	RW		11 = Reserved	
1	Reserved					
0	Reserved					





# **Byte 14: OE Termination Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	OE0_term1	OE0 Pull up or down	RW	0	00=None	10= Pullup
6	OE0_term0	OE0 Pull up or down	RW	1	01=Pulldown	11=Pullup and Down
5	Reserved			0		
4	Reserved			1		
3	Reserved			0		
2	Reserved			1		
1	Reserved			0		
0	Reserved			1		

### **Byte 15: OE Termination Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			1		
5	Reserved			0		
4	Reserved			1		
3	OE1_term1	OE1 Pull up or down	RW	0	00=None	10= Pullup
2	OE1_term0	OE1 Pull up or down	RW	1	01=Pulldown	11=Pullup and Down
1	Reserved			0		
0	Reserved			1		

#### **Byte 16: Power Good Termination Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:2	Reserved			0x09		
1	PWRGD_PD1	Clock Power Good and Power Down Pull up or	RW	1	00=None	10= Pullup
0	PWRGD_PD0		RW	0	01=Pulldown	11=Pullup and Down





#### Byte 17: Reserved

#### **Byte 18: Enable Pin Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	OE1_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
4	Reserved			0		
3	OE0_Enable	Sets Enable High or Low	RW	0	Enable = Low	Enable = High
2	Reserved			0		
1	Reserved			0		
0	Reserved			0		

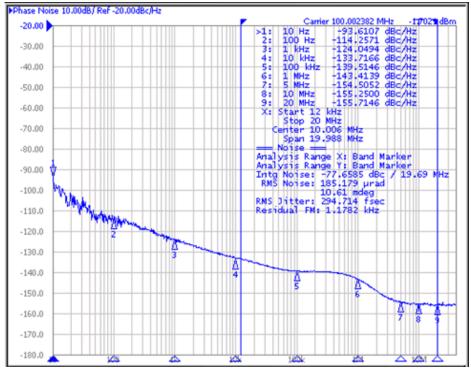
#### **Byte 19: Power Down Pin Control**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:1	Reserved			0		
0	PWRGD_PD	PWRGD_PD Active via Pull up or Pull down	RW	0	Power Down = Low	Power Down = High

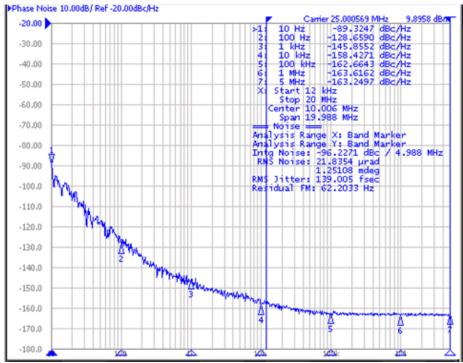




## **Plots** 100MHz HCSL Clock (12k to 20MHz)

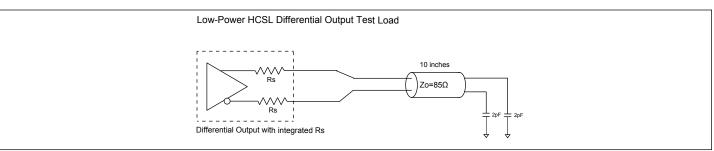


# 25MHz CMOS Clock

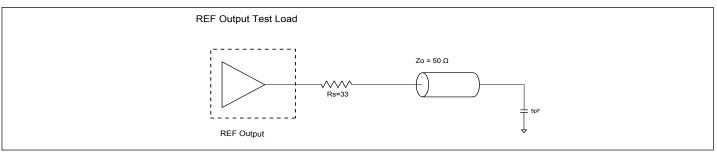




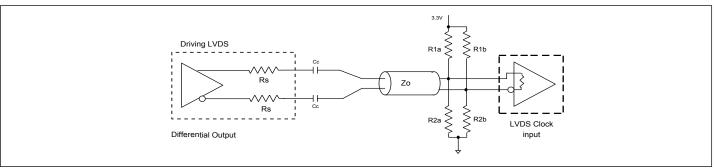




#### Figure 1. Low Power HCSL Test Circuit



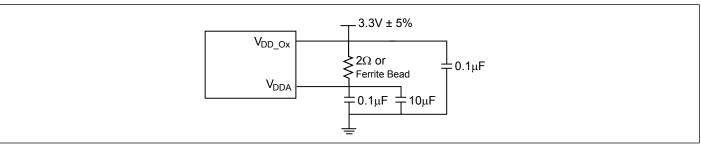
#### Figure 2. CMOS REF Test Circuit



#### Figure 3. Differential Output driving LVDS

### Alternate Differential Output Terminations ( $Z_0 = 85\Omega$ )

Component	Receiver with termination	Receiver without termination	Unit
R <sub>1a</sub> , R <sub>1b</sub>	10,000	130	Ω
$R_{2a}, R_{2b}$	5,600	64	Ω
C <sub>C</sub>	0.1	0.1	μF
V <sub>CM</sub>	1.2	1.2	V



# Figure 4. Power Supply Filter

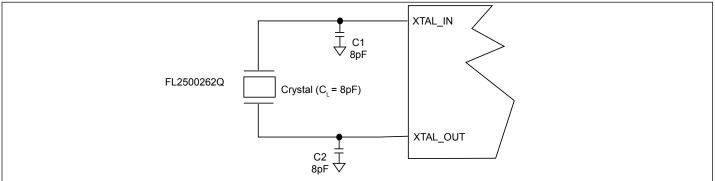




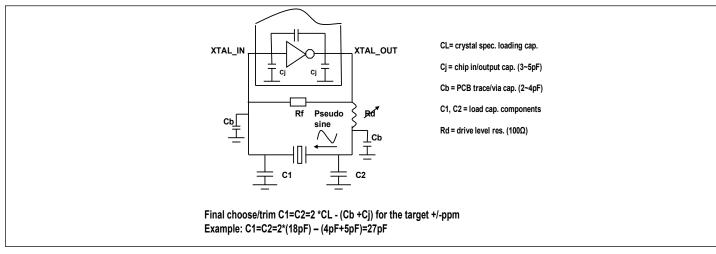
# **Crystal circuit connection**

The following diagram shows PI6CG33202C crystal circuit connection with a parallel crystal. For the CL=8pF crystal, it is suggested to use C1=8pF, C2=8pF. C1 and C2 can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

#### **Crystal Oscillator Circuit**



### **Crystal Capacitor Calculation**



# **Recommended Crystal Specification**

#### **Diodes recommends:**

- a) FL2500217, SMD 3.2x2.5(4P), 25MHz, CL=8pF, +/-20ppm, https://www.diodes.com/assets/Datasheets/FL.pdf
- b) FH2500016, SMD 2.5x2.0(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FH.pdf
- c) FW2500031, SMD 2.0x1.6(4P), 25MHz, CL=8pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/FW.pdf
- d) US2500003, SMD 1.6x1.2(4P), 25MHz, CL=12pF, +/-30ppm, https://www.diodes.com/assets/Datasheets/US.pdf





## **Thermal Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
$\theta_{JA}$	Thermal Resistance Junction to Ambient	Still air			54.4	°C/W
$\theta_{JC}$	Thermal Resistance Junction to Case				40.8	°C/W

# **Part Marking**

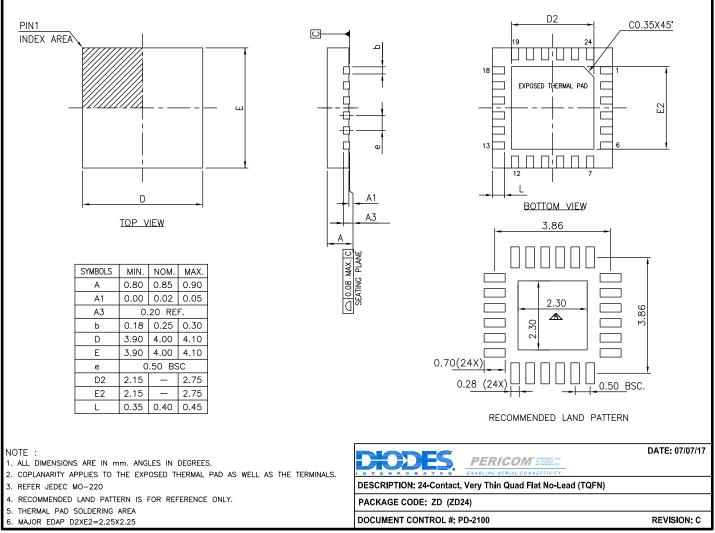


Y: Year W: Workweek 1st X: Assembly Code 2nd X: Fab Code





# Packaging Mechanical: 24-TQFN (ZD)



#### 17-0533

#### For latest package info.

please check: http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/

#### **Ordering Information**

Ordering Code	Package Code	Package Description	Pin 1 Location
PI6CG33202CZDIEX	ZD	24-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Right Corner
PI6CG33202CZDIEX-13R	ZD	24-Contact, Very Thin Quad Flat No-Lead (TQFN)	Top Left Corner

#### Notes:

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.

2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

4. E = Pb-free and Green

5. X suffix = Tape/Reel

6. For packaging details, go to our website at: https://www.diodes.com/assets/MediaList-Attachments/Diodes-Package-Information.pdf





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